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The fiftieth anniversary of the first applications of the scanning electron microscope in materials research

Pages 3-12
Kenneth C.A. Smith, Oliver C. Wells, Dennis McMullan

Lens theory of non-paraxial rays for electron gun characterization

Pages 13-33
Shin Fujita, Masahiro Takebe, Hiroshi Shimoyama

Numerical analyses of space charge and surface field of a point cathode electron gun

Pages 35-42
R. Iiyoshi

**Performance evaluation of the magnetic field immersion type field emission gun by boundary element method**

*Pages 43-49*
Keiji Tamura, Takashi Ikuta, Ryuichi Shimizu, Mikio Ichihashi

**Electrospray ionisation source incorporating electrodynamic ion focusing and conveying**

*Pages 51-60*
Alex W. Colburn, M.P. Barrow, M.C. Gill, A.E. Giannakopulos, Peter J. Derrick

**Simulation of secondary electron emission in an electron gun**

*Pages 61-64*
Meng Jin, Wei Lei, Xiaobing Zhang, Yan Tu, Hanchun Yin, Zichen Zhang

**Study of the movement of electron groups near a field emission cathode**

*Pages 65-70*
Lei Wei, Zhang Xiaobing, Lou Chaogang, Tu Yan, Yin Hanchun, Zichen Zhang, Lifang Zhang, Xing Su, Chi Li

**Possibilities for graphene for field emission: modeling studies**
using the BEM

Pages 71-75
S. Watcharotone, R.S. Ruoff, F.H. Read

“Equivalent cylinder” model for electron guns

Pages 77-85
O.D. Potapkin

Stable ion beam transport through periodic electrostatic structures: linear and non-linear effects

Pages 87-97
Anatoli Verentchikov, Alexander Berdnikov, Mikhail Yavor

The beam control in quadrupole probe-forming systems with allowance of correlation between angular distribution and energy spread of charged particles

Pages 99-104
A.G. Ponomarev, V.I. Miroshnichenko, V.E. Storizhko

Design of the low energy beam transport section of the high current injector

Pages 105-111
A. Mandal, G. Rodrigues, D. Kanjilal, A. Roy
**Automatic measurement of electron-beam diameter and astigmatism: BEAMETR**

*Pages 113-118*
S. Babin, M. Gaevski, D. Joy, M. Machin, A. Martynov

**In-situ beam metrology in shaped-beam lithography tool**

*Pages 119-126*
Takashi Kamikubo, Kenji Ohtoshi, Steven Golladay, Victor Katsap, Rodney A. Kendall, Hitoshi Sunaoshi, Shuichi Tamamushi

**Relation between optimal focus condition and a pixel size or an image magnification in a digital SEM**

*Pages 127-133*
Mitsugu Sato, Takeshi Ogashiwa

**The ALIS He ion source and its application to high resolution microscopy**

*Pages 135-141*
Raymond Hill, John Notte, Bill Ward

**Helium ion microscope invasiveness study and novel imaging analysis for semiconductor applications**

*Pages 143-148*
Richard H. Livengood, Michael Grumski, Yuval Greenzweig, Ted Liang, Robert Jamison, Qianghua Xie
Electron beam computed tomography: Challenges and opportunities

Pages 149-154
Michael Retsky

Elemental identification using transmitted and backscattered electrons in an SEM

Pages 155-160
T. Luo, A. Khursheed

The energy dispersion characteristics of a magnetic beam separator

Pages 161-166
Hung Quang Hoang, A. Khursheed

Aberration-corrected optics: from an idea to a device

Pages 167-178
Heiko Müller, Stephan Uhlemann, Peter Hartel, Maximilian Haider

Optimized Quadrupole-Octupole $C_3/C_5$ Aberration Corrector for STEM
Pages 179-183
N. Dellby, O.L Krivanek, M.F. Murfitt

**Computer simulations of hexapole aberration correctors**

Pages 185-191
L.A. Baranova, F.H. Read, D. Cubric

**The use of multipole fields for aberration correction in π/2 Wien filters**

Pages 193-198
G. Martinez, K. Tsuno

**Design and analysis of a thermionic SEM column using 3D finite element analysis**

Pages 199-205
Man-Jin Park, Keun Park, Dong Hwan Kim, Dong Young Jang

**On electron movement through magnetic electron lens**

Pages 207-215
A.A. Melnikov, O.D. Potapkin

**New approach to the problem of Coulomb interaction in electron and ion bunches**
Global optimized reconstruction of off-axis electron hologram using genetic algorithms

Microcolumn operation for high current probe beam with enhanced beam energy

Improvement of FDM by extrapolation on multiple grids

Calculation of fields of magnetic deflection systems with FEM using a vector potential approach — Part I: stationary fields
using a vector potential approach — Part II: time-dependent fields

Pages 257-264
T. Elster, D. Stahl, P. Hahmann

Improving extraction and transport simulations of the superconducting ECR ion source VENUS

Pages 265-272
D.S. Todd, D. Leitner, C. Pint, D.P. Grote

Spatial and temporal focusing of femtosecond electron bunches in time-dependent electric fields

Pages 273-283
Sergei A. Andreev, Dmitriy E. Greenfield, Mikhail A. Monastyrskiy, Victor A. Tarasov

About field calculation of multi-electrode systems with symmetry $C_{nv}$

Pages 285-289
G.A. Doskeev, I.F. Spivak-Lavrov

Investigation of Spatial Time-of-Flight Focusing Properties of the Electrostatic Transaxial Mirror with Curvilinear Axial Trajectory
Simulation of electron mirrors by the differential algebraic method

CHARIOT: Software tool for modeling SEM signal and e-beam lithography

A new program for the design of electron microscopes

Computer program TRIO 2.0 for calculation and visualization of ion trajectories

Mathematica program for extracting one turn Lie generator
map. application of TPSA

Pages 333-338
Dobrin Kaltchev

Software for designing multipole aberration correctors

Pages 339-353
Haoning Liu, John Rouse, Liping Wang, Eric Munro

The temptation of field emission displays

Pages 355-365
Daniel den Engelsen

Study of decreasing the driving voltage of HOPFED

Pages 367-370
Chi Li, Wei Lei, Baoping Wang, Xiaobing Zhang, Zichen Zhang, Hanchun Yi, Yan Tu, Lifang Zhang, Xing Su

Enhancement of anode current in an HOPFED

Pages 371-374
Lifang Zhang, Xiaobing Zhang, Wei Lei, Xing Su, Chi Li, Zichen Zhang, Hanchun Yin, Yan Tu
Investigation of the focus characteristics of a triode structure in FED

Pages 375-378
Zichen Zhang, Wei Lei, Xiaobing Zhang, Baoping Wang, Hanchun Yin, Yan Tu

Efficient multiple beam ion optics for quantitative surface analysis: from simulations to a fully operational instrument

Pages 379-389
Igor V. Veryovkin, C. Emil Tripa, Michael J. Pellin

Planar multi-reflecting time-of-flight mass analyzer with a jigsaw ion path

Pages 391-400
Mikhail Yavor, Anatoli Verentchikov, Juri Hasin, Boris Kozlov, Mikhail Gavrik, Andrey Trufanov

Development of a tandem time-of-flight mass spectrometer “MULTUM-TOF/TOF” at Osaka University: Combination of a multi-turn time-of-flight mass spectrometer and a quadratic-field ion mirror

Pages 401-411
Michisato Toyoda, Anastassios E. Giannakopulos, Alex W. Colburn, Peter J. Derrick

TOF electron energy analyzer for spin and angular resolved
photoemission spectroscopy

Pages 413-423
G. Lebedev, C. Jozwiak, N. Andresen, A. Lanzara, Z. Hussain

Calculation of a mass-spectrometer with a sector magnet, an electrostatic prism and a transaxial lens

Pages 425-433
O.A. Baisanov, G.A. Doskeev, I.F. Spivak-Lavrov

Some common properties of corpuscular-optical systems with a mean plane

Pages 435-442

Optimum design of E×B mass separator in three dimensions

Pages 443-450
Wen-Ping Li, Li Han, Wen-Qi Gu

Simulation of curved axis systems

Pages 451-459
John A. Rouse, Eric Munro, Liping Wang, Haoning Liu
Modelling SIMION’s accuracy for hemispherical deflector analyzers using a spherical capacitor

Pages 461-466
T.J.M. Zouros, F.M. Spiegelhalder, David J. Manura

First-order focusing and energy resolution optimization of a biased paracentric hemispherical spectrograph

Pages 467-472
Omer Sise, Theo J.M. Zouros, Melike Ulu, Mevlut Dogan

Comparison of fringing field correction schemes for the 180 hemispherical deflector analyzer

Pages 473-477
Omer Sise, Theo J.M. Zouros, Melike Ulu, Mevlut Dogan

Energy width reduction using an electrostatic $\Omega$ - monochromator

Pages 479-483
Jan Bärtle, Erich Plies

Electron optics for low energy electron microscopy

Pages 485-504
Marian Mankos, David Adler, Lee Veneklasen, Eric Munro
Image properties in an aberration-corrected photoemission electron microscope

Pages 505-511

Design of a chromatic aberration corrected time-of-flight electron emission microscope (TOFEEM)

Pages 513-519
Anjam Khursheed, Ding Yu

An energy stabilizing system for electron energy-loss spectrometers in transmission electron microscopy

Pages 521-527
Zhiwei Wang, Shu Hu, Chen Xu, Dennis McMullan, Jun Yuan

Initial results on the spectroscopic SEM concept

Pages 529-535
Mans Osterberg, Anjam Khursheed

Electrostatic micro-lens within an AFM cantilever for LEEM

Pages 537-543
Arthur M. Blackburn
Dynamic blanking control of single column multi-electron-beam system

Pages 545-552

Design of a high brightness multi-electron-beam source

Pages 553-563
Yanxia Zhang, P. Kruit

3D microscopic model of electron amplification in microchannel amplifiers for maskless lithography

Pages 565-572
Anton S. Tremsin, Harry F. Lockwood, David R. Beaulieu, Neal T. Sullivan, Eric Munro, John Rouse